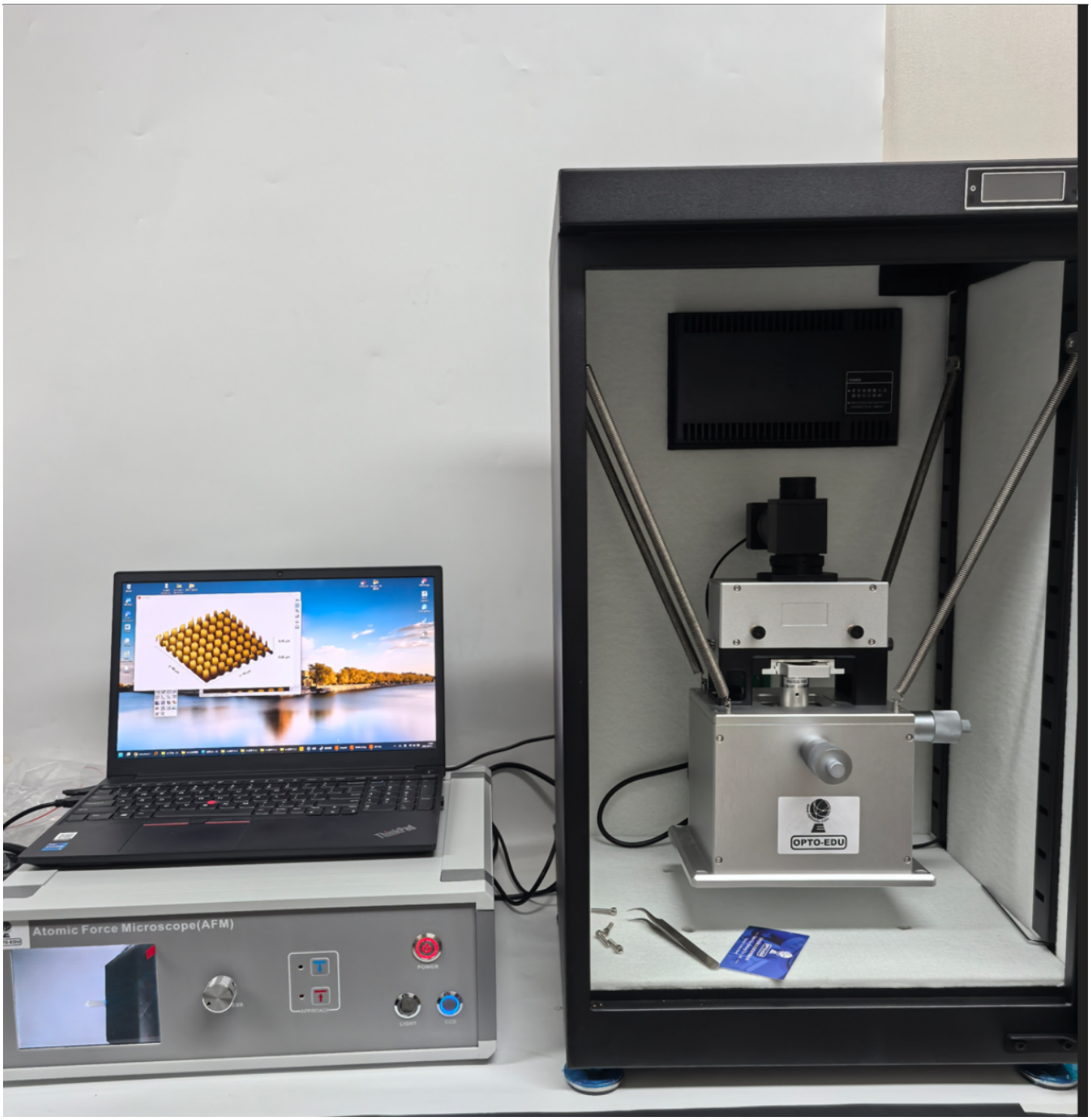
Opto-Edu A62.4503 AFM Successfully in Iraq, Demonstrating Chinese Manufacturing Excellence in Scientific Equipment

Opto-Edu announced that its **A62.4503** Atomic Force Microscope (AFM) was successfully delivered & installed in Iraq customer's laboratory early December 2025.

Precision Design and Exceptional Performance

The A62.4503 Atomic Force Microscope (AFM) incorporates multiple innovative technologies specifically designed for nanoscale material characterization. As shown in the product images, the equipment features a sophisticated integrated structure design that combines the laser detection head with the sample scanning stage, support both Contact Mode, Tapping Mode, it significantly enhancing system stability and anti-interference capabilities.



Core Technical Advantages

- Basic Level, Separate Controller & Main Body Design, With Contact Mode,

Tapping Mode

- Contact Mode, Tapping Mode, Scan Range XY 50x50um, Z 5um, Scan Resolution XY 0.2nm, Z 0.05nm

- Sample Size Dia.